

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10790453	MATSUYAMA ET AL.
	<b>Examiner</b> Lee, Siu M	<b>Art Unit</b> 2611

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	316, 344	3/22/2007	Siu M. Lee

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST	3/22/2007	Siu M. Lee
Discuss the application with Chieh Fan	3/30/2007	Siu M. Lee

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>